# Electrochemical equivalent circuit modeling using LTSPICE XVII for EGFET pH sensor based on TiO<sub>2</sub> sensing electrode experimental value

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### Abstract

The design and simulation of an electrochemical equivalent circuit for an extended-gate field-effect transistor (EGFET)based pH sensor was presented in this paper. The pH sensor is essential in various fields, such as biomedical applications, environmental monitoring, and industrial processes. The proposed sensor utilized the EGFET structure to measure pH with high sensitivity and precision. In this study, an electrochemical equivalent circuit was developed to model the EGFET pH sensor behavior. The circuit comprised various components, including resistors, capacitors, and voltage sources, representing the electrical characteristics of the pH sensor. The circuit was simulated using LTSPICE XVII, a widely-used electronic circuit simulator. Experimental values obtained from actual pH measurements are utilized to validate the accuracy of the proposed electrochemical equivalent circuit. The simulated results are compared against the experimental data to ensure the circuit accurately captured the behavior of the pH sensor. The simulation allowed for a detailed analysis of the sensor performance under different pH conditions and optimized the sensor design parameters. It was found that the experimental transfer and output characteristics of the EGFET were very similar to those from the simulation program with integrated circuit emphasis (SPICE) simulation, and gate-to-source voltage (VGS) value at 3 V exhibited the value of drain current, ID at 234.002 µA, which is similar to the transfer characteristic of CD4007UBE using semiconductor device analyzer (SDA). Other than that, the changes in value components in the equivalent circuit did not affect the transfer and output characteristics graph. Still, the capacitor value produced significant output variation in the simulation. This can be related to the modification on the equivalent circuit with additional voltage, source to bulk (VSB), to produce the different threshold voltage (VT) values at different pH.

### **Keywords**

Electrochemical, Equivalent circuit, EGFET, LTSPICE XVII, pH sensor.

### **1.Introduction**

An electrochemical sensor has gained significant attention due to its ability to translate ion analysis into an existing signal, potential difference, and impedance. This method is commonly used due to its simple operation, good sensitivity, easy miniaturization, and low power consumption. The technique has been used for in situ quantitative analysis and real-time monitoring of environmental parameters.

It can be divided into three categories, voltammetric, impedimetric, and potentiometric, depending on the details of the experimental design [1-9]. For potentiometric, the electrostatic potentials (volt (V)) are measured and do not involve current in the measurement. While for voltammetric and impedimetric, current measurement is involved, and the electrode's potential was held or used as a variable input during measurement. While for voltammetric and impedimetric, current measurement is involved and the electrode's potential was held or used as a variable input during measurement.

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One of the sensors developed based on the electrochemical concept is the ion-sensitive field effect transistor (ISFET) sensor, usually associated with pH sensing. The basic configuration of ISFET is derived from a metal-oxide-semiconductor field-effect transistor (MOSFET), in which the metal gate is substituted by an ion-sensitive membrane with direct contact with a buffer solution [10]. However, the ISFET still suffers from several disadvantages, including device instability and poor sensitivity [11]. However, these disadvantages can be overcome by the extended-gate field effect transistor (EGFET) structure.

EGFET was proposed by Lauks et al. in 1983 [12]. EGFET structure isolated the field effect transistor (FET) from the chemical environment, in which a chemically sensitive membrane (or sensing electrode (SE)) was deposited at the end of the signal line extending from the FET gate electrode [13]. It offers several advantages, such as light insensitivity, simpler packaging, and flexibility for the shape of the extended gate area, as reported by [13–18]. EGFET has been applied in an extensive range of applications to detect any substance, especially as biosensors. EGFET is also favorable because it can be characterized using the simple connection and flexibility of the extended gate design [19].

Computer-aided design (CAD) tools have made the simulation of semiconductor-based devices possible before going through the complex fabrication process [20–23]. The CAD will reduce the cost and also the design cycle. A simulation program with integrated circuit emphasis (SPICE) is a CAD tool with built-in models for active devices like MOSFETs and bipolar junction transistors (BJTs). Martinoia et al. [24] introduced the first ISFET SPICE macromodel using a generalized SPICE model. They incorporated silanol and primary amine binding sites and evaluated device performance by modifying the model card of a metal oxide transistor. The model was used to study nonideal effects such as hysteresis and partial insensitivity to pH. The BIOSPICE model was further modified to incorporate transient dependence, and a thermal model was developed to account for temperature effects. The simulated results matched well with experimental studies of ISFET devices. However, the SPICE model's implementation was limited, with unavailable source code and complex compilation requirements. Then, the macromodel of ISFET in SPICE was further developed by Martinoia and Massobrio [25]. They came out with the original SPICE-2G and created BIOSPICE, which contains a

built-in Physico-chemical model to deal with electrochemical devices such as ISFET-based sensors. Abu et al. [26] came out with an ISFET macromodel that contributed as a new subcircuit block for the LTSPICE component library to design ISFET-based sensors or microsystems. Unlike other authors, Kwon et al. [27] developed a macromodel for ISFET that addresses the issue of current drift. Their model represented the FET as two capacitors, one with a pure gate-oxide capacitance (C1) allowing slow movement of hydrogen ions and the other with a defective gate-oxide capacitance (C2), enabling relatively faster ion movement. The drift effect is represented by the movement of hydrogen ions in the defective oxide, denoted as R2, connected in parallel with C2. The current drift model included a series combination of the electrolyte resistance (R1) and a parallel combination of R2, C2, and C1. The model was experimentally validated using the transient current characteristics of a fabricated silicon nanowire pH sensor. The results demonstrated that the drift in the sensor is caused by the enhanced penetration of hydrogen ions through the defective oxide layer under the influence of an electric field.

Thus, the development and simulation of electrochemical equivalent circuits have been extensively explored for ISFET sensors [28-34], but the discussion on EGFET sensors has been relatively limited. This created a gap in knowledge and understanding, as EGFET sensors offer distinct advantages over their ISFET counterparts, including improved stability, sensitivity, and flexibility in design. The challenges in designing and simulating an electrochemical equivalent circuit for EGFET sensors using LTSPICE lie in capturing the complex electrochemical phenomena that occur at the interface of the SE and the solution. This involves considering various factors, such as ion selectivity, double-layer capacitance, charge transfer resistance, and diffusion processes.

So, this paper aims to study the equivalent circuit of the electrochemical method with an EGFET structure setup simulated using LTSPICE XVII by considering the fundamental electrochemical processes and incorporating experimental values. The simulation results obtained from the circuit model will facilitate optimizing the EGFET sensor design, enabling improved sensitivity, response time, and selectivity. In addition, based on the theoretical knowledge of the EGFET the characteristic mechanism, and relationship of resistor and capacitor representing SE and reference electrode (RE) were studied.

This paper is organized in several sections, starting with an introduction in Section 1, followed by a literature review in Section 2. Section 3 explains the design methodology for implementing the equivalent circuit, while Section 4 provides an in-depth analysis of the results. Section 5 discusses various characteristics and limitations. Finally, the paper concludes with Section 6.

# **2.Literature review**

### 2.1Modeling and simulation setup

Most of the reported ISFET behavioral macromodel comprised two main stages: the electrochemical stage and the electronic stage [35, 36]. The electrochemical stage included the RE and the electrical double-layer capacitance, while the electronic stage involved an nchannel MOSFET. The equivalent circuit of an ISFET that represented the electrochemical and electronic stages was a capacitor, which was based on Fick's first law of diffusion, the Gouv-Chapman-Stern-Graham model, and the Shockley-Read-Hall model [37-39]. ISFET equivalent circuits use Fick's first law of diffusion describes the rate at which a substance diffuses through a medium, which may apply to the ISFET's solution ions. This law compensates for the sensor's ion diffusion processes in the circuit model. The Gouy-Chapman-Stern-Graham model also affects ISFET equivalent circuit representation. This model describes ion behavior at the solid-solution interface. The electrical double layer at the solid surface and ion-charged surface interaction is considered. This model highlights the ISFET's sensing interface electrochemical processes when added to the circuit. In semiconductor physics, the Shockley-Read-Hall model describes charge carrier recombination and generation. It incorporates semiconductor material imperfections or impurities that modify charge flow. The ISFET's equivalent circuit addresses electronic stages and charges carrier behavior in the transistor structure by including this model. In general, the integration of different scientific models into the equivalent circuit depiction of an Ion-sensitive field effect transistor (ISFET). The circuit aims to capture the electrochemical and electronic processes involved in the functioning of the ISFET by utilizing Fick's first law of diffusion, the Gouy-Chapman-Stern-Graham model, and the Shockley-Read-Hall model. The detailed circuit diagram aids in comprehending the sensor's actions and simplifies the process of analyzing and interpreting its readings [31] and [40-42].

Thus, this paper used the basic configuration of potentiometric measurement, as shown in *Figure 1*. The basic configurations consist of RE and ion-selective electrodes (ISE), which convert a particular ionic activity to a specific potential. The potentiometric measurement measures the voltage difference between RE and ISE when both electrodes are dipped in the same buffer solution or electrolyte. The characteristic of ISE controls the ionic activity called response and can be related to the Nernst equation, as shown in Equation 1[43].

$$E(T) = E^{o}(T) - 2.303 \text{ RT/nF pH}$$
 (1)

Where,

E(T)=Measured potential mV at temperature T (Kelvin)

E°(T)=Constant, standard potential mV at temperature T (Kelvin)

2.303 = Factor to convert ln to log

R=Molar gas constant (8.3144 J mol<sup>-1</sup> K<sup>-1</sup>)

F = Faraday constant 96485 C mol<sup>-1</sup>

T= Temperature K (kelvin)



Figure 1 The basic configuration of the potentiometric measurement

The Nernst equation is a mathematical description of an ideal pH electrode in electrochemistry [44]. It can accurately predict cell potentials only as the equilibrium quotient is expressed in activities. The sensor is considered good if the sensitivity value is near the theoretical Nernstian value of 59.20 mV/pH and the linearity value is near 1. *Figure 2* shows the potentiometric equivalent circuit consisting of resistors and capacitors. By referring to *Figure 2*, the resistor ( $R_{REF}$ ) and capacitor ( $C_{REF}$ ) in parallel represent the RE, and the resistor (R1) and capacitor (C1) in parallel represent the ISE. In contrast, the resistor (Rs) in series between the two parallel components represents the buffer solution or electrolyte. The value of the potential difference between RE and ISE at different solution buffers is measured by a voltmeter (V).



Figure 2 Potentiometric equivalent circuit

The capacitor components in this equivalent circuit can be described with the Helmholtz double layer, which represents the accumulation of electrical charges present at the boundary of an electrode and electrolyte when they are in contact with each other as in *Figure 1*. The arrangement of positive and negative charges at the surface of the electrode leads to the capacitive behavior of charge storage [44]. While the resistor's role is to oppose the electrical current through it. This is called the resistance of electricity, which is measured in the ohm unit. The capacitance (C) and resistance (R) relationship are shown in Equation 2 and Equation 3;

$$C = q/V \tag{2}$$

$$R = V/I \tag{3}$$

Where,

C = capacitance of the capacitor, Farads (F) q = charge stored, Coulombs (C) V = voltage, Volts (V)  $R = resistance, Ohms (\Omega)$ I = current, Amperes (A)

#### 2.2Electrochemical equivalent circuit

*Figure 3* shows the experimental EGFET measurement setup. The RE was connected to a semiconductor device analyzer (SDA) Keysight B1500A, while the SE was connected to the gate of a

commercialized MOSFET CD4007 as the extended gate SE.

This MOSFET is well documented in terms of width and length in the SPICE model, and the connectivity of this MOSFET is also versatile. The transfer and output characteristics were obtained from this measurement setup.



Figure 3 EGFET measurement setup

*Figure 4* shows the internal schematic circuit of CD4007 MOSFET. The CD4007 consists of 3 pairs inverter with pin 14 as a P-type metal oxide semiconductor (PMOS) and pin 7 as an N-type metal oxide semiconductor (NMOS). This inverter shares a common pin gate (6, 3, and 10). Pins 6, 7, and 8 were used for this measurement. Other pins (3, 4, 5, 10, 9, and 12) also can be used for measurement setup.



Figure 4 Schematic circuit CD4007 MOSFET

The EGFET equivalent circuit as shown in *Figure 5*, has been constructed by considering the potentiometric equivalent circuit (*Figure 2*). The difference between *Figure 2* and *Figure 5* is, *Figure 5* has additional NMOS MOSFET representing CD4007 that gate connected to sensing capacitor (C1) and resistor (R1) while reference voltage,  $V_{REF}$  connected to reference capacitor ( $C_{REF}$ ) and resistor ( $R_{REF}$ ).



Figure 5 EGFET equivalent circuit

Figure 6 shows the basic reaction on metal oxide surface producing surface potential at (a) neutral, (b) acidic, and (c) alkaline conditions. As shown in Figure 6, the surface of metal oxide has a hydroxyl group and these hydroxyl groups are capable of interacting with pH potential determining ions (PDI) which are hydrogen ions (in an acidic solution) and hydroxide ions (in a basic solution). Depending on the type of PDI that is dominant in the solution, the surface of the sensing membrane will be either more positively or negatively charged. This positive and negatively charged can be represented by the capacitor C1 in EGFET equivalent circuit (Figure 5). The change of ion is detected based on the changes in capacitance. Therefore, the capacitance shall determine the amount of charge that can be adsorbed on the capacitor. In EGFET equivalent circuit, resistors RREF and R1 act as the charge transfer resistance and RS is the solution resistance.



**Figure 6** Basic reaction on metal oxide surface producing surface potential at (a) neutral, (b) acidic, and (c) alkaline conditions

### **3.Methodology 3.1Simulation of EGFET equivalent circuit**

*Figure* 7 shows a block diagram representation flow of this project. This block diagram demonstrates the sequential process of arranging discrete components involving a resistor and capacitor connected to MOSFET, setting up MOSFET parameters, and simulating the  $I_D$  versus  $V_{GS}$  graph for an equivalent EGFET circuit. Each step contributes to the overall understanding and analysis of the circuit's functionality and performance.

Thus, in this simulation part, LTSPICE XVII was used to simulate the EGFET equivalent circuit and studied each component's characteristics and the current-voltage relationship to (I-V) characteristic. Before running the simulation, CD4007 MOSFET was modeled by setting up the parameters of the MOSFET, such as width (W), length (L), transconductance (K), lambda ( $\lambda$ ), and V<sub>T</sub> as shown in Table 1. This model was selected to compare with the simulation and experimental results.



Figure 7 Block diagram flow of this project

Table	1	MOSFET	parameters	for	LTSPICE
simulat	ion				

Mosfet Parameters	Value
WIDTH (W)	170 μm
LENGTH (L)	10 µm
TRANSCONDUCTANCE (K)	$74.33 \times 10^{-6} \text{ S}$
LAMBDA (λ)	0.01
THRESHOLD VOLTAGE (V <sub>T</sub> )	1.1

*Figures 8* and *9* show the experimental output and transfer characteristics of CD4007UBE MOSFET, respectively, measured using SDA. The drain-to-source voltage ( $V_{DS}$ ) value varied from 1 to 3 V and  $V_{GS}$  was fixed at 2V for output characteristics. While for transfer characteristics,  $V_{GS}$  was varied from 1 to 3 V, and  $V_{DS}$  was set at 100 mV.

As shown in *Figure 8*, there are three state regions: triode, linear, and active. When the  $V_{DS}$  is smaller, the CD4007UBE operates in the triode region. In this mode, the drain current is directly proportional to  $V_{DS}$  and can be described using Ohm's Law.

As a result, the characteristic output curve in the triode region slopes upward, demonstrating a linear relationship between  $I_D$  and  $V_{DS}$ . While in the saturation region or linear region, the  $V_{DS}$  is sufficiently large, causing the CD4007UBE to operate in saturation mode. In this mode, the drain current remains relatively constant regardless of further increases in  $V_{DS}$ . As a result, the characteristic output curve appears flat in the saturation region, indicating high current stability. These regions represent by the given formula as shown in Equation 4, Equation 5, and Equation 6 as follows:

$$I_{D} = \mu_{n}C_{ox} W/L (V_{GS} - V_{t})V_{DS; \text{ Triode region}} (4)$$
$$I_{D} = \mu_{n}C_{ox} W/L [(V_{GS} - V_{t})V_{DS} -$$

 $V^2_{DS}/2$ ]; Linear region (5)

 $I_D = 1/2 \,\mu_n C_{ox} \,W/L \,(V_{GS} - V_t)^2; \text{ The active region}$ (6)

 $K = \mu_n C_{ox}$ ; Transconductance

Where  $I_D$  is the drain current,  $\mu_n$  is the mobility,  $C_{ox}$  is the oxide capacitor, W is width, L is length,  $V_{GS}$  is the gate-source voltage,  $V_{DS}$  is the drain-source voltage, and  $V_T$  is the threshold voltage.

Three formulas represent three conditions from *Figure 8*: cut-off, linear, and saturation regions. In summary, the linear, active, and triode regions describe different modes of operation for a FET and the corresponding relationship between the voltage applied to the transistor and the resulting current flowing through it.



Figure 8 Output characteristic ( $I_D$  versus  $V_{DS}$ ) of CD4007UBE using Semiconductor Analyzer

Equation 7, Equation 8, and Equation 9 describe the condition, respectively. The cut-off region where  $V_T$  is less than or equal to  $V_{GS}$ . The transistor is in an off state in the cut-off region, meaning there is no significant current flow between the source and drain terminals. This occurs when the applied  $V_{GS}$  is lower than the  $V_T$  of the transistor. The transistor acts as an open switch in this region, and the  $I_D$  is nearly zero. While for a linear region,  $V_{GS}$  greater than  $V_T$ . In this region, the transistor behaves as a voltage-controlled resistor.

The  $V_{GS}$  applied is higher than  $V_T$ , resulting in a conducting channel between the source and drain. The  $I_D$  increases linearly with  $V_{GS}$ , following Ohm's Law. The drain current is directly proportional to the  $V_{DS}$  as long as  $V_{DS}$  is not excessively large.

As shown in *Figure 9*, the value of  $V_T$  was around 1.1 V, and at  $V_{GS}$  3 V. The value of  $I_D$  was around 234  $\mu$ A. W and L values were assumed and fixed to 170  $\mu$ m and 10  $\mu$ m, respectively. The value of  $\lambda$  was also assumed to be 0.01. *Figure 10* shows the EGFET equivalent circuit with parameters.



Figure 9 Transfer characteristic ( $I_D$  versus  $V_{GS}$ ) of CD4007UBE using Semiconductor Analyzer



.MODEL NMOS NMOS (L=10u W=170u VTO = 1.1 Kp = 74.33e-6 LAMBDA = 0.01) Figure 10 EGFET equivalent circuit with parameters

$$\begin{split} I_{D} &= 0; V_{GS} \leq V_{T} ; \text{Cut Off} & (7) \\ I_{D} &= K \, W/L \left[ (V_{GS} - V_{t}) V_{DS} - V_{DS}^{2}/2 \right] (1 \\ &+ \lambda V_{DS}); V_{GS} > V_{T}, V_{DS} \\ &\leq V_{GS} - V_{T}; \text{ Linear region} \\ I_{D} &= K \, W/L \, (V_{GS} - V_{t})^{2} (1 + \lambda V_{DS}); V_{GS} > V_{T} \, V_{DS} \\ &> V_{GS} - V_{T} \text{Saturation region} \\ & (9) \end{split}$$

By referring to Equation 7, the value of  $V_{GS}$  (3 V) is greater than  $V_T$  (1.1 V), and in the other condition, the value of  $V_{GS} - V_T$  (3-1.1) is greater than  $V_{DS}$  (100 mV). Based on these conditions, the value of transconductance, K, can be calculated using the formula and found to be 74.33 $\mu$ . Therefore, all these parameters W (170  $\mu$ m), L (10  $\mu$ m), K (74.33  $\mu$ S),  $V_T$ (1.1 V), and lambda (0.01) were set in LTSPICE simulation as shown in *Figure 9*.

In this paper, the simulation was carried out for  $I_D$  versus  $V_{GS}$  at fixed  $V_{GS}$  at 3V, and  $I_D$  versus  $V_{DS}$  for  $V_{GS}$  fixed at 2V, with different capacitor and resistor

values. The simulations involved using various capacitor and resistor values, which suggests that the study aimed to analyze the impact of varying circuit components on the behavior of the MOSFET. Other than that, the output current for variation of equivalent circuits, input and output characteristics at different pH levels, and input and output characteristics for different  $V_{REF}$  also were studied.

### **4.Results**

**4.1Graph analysis on simulation and experimental** *Figures 11 and 12* are the  $I_D$  versus  $V_{GS}$  and  $I_D$  versus  $V_{DS}$  for EGFET equivalent circuit parameters for this simulation part. These parameters are defined based on the EGFET model and are represented in *Figure 10*. Specifically, *Figure 11* shows the output characteristic obtained through measurements using an SDA. *Figure 11* indicates that the  $I_D$  at a  $V_{DS}$  of 2V is measured to be 307  $\mu$ A. However, it is observed that the simulation shows a higher value of  $I_D$  at 2V, measuring over 500  $\mu$ A. This discrepancy between the measured and simulated values indicates a difference between the actual device behavior and the model used in the simulation.



**Figure 11** Simulation ID versus VDS graph at VREF 2V



Figure 12 Simulation I<sub>D</sub> versus V<sub>GS</sub> graph

The value of  $I_D$  closed to 307  $\mu$ A when the V<sub>GS</sub> value at 1.8 V. So, it can be said that the simulation part and the actual are set to be in the same condition. Even though  $I_D$  values are slightly different between simulation and using SDA, this value is acceptable. *Figure 12* shows that V<sub>GS</sub> at 3 V exhibited the value of  $I_D$  at 234.002  $\mu$ A, which is similar to the transfer characteristic of CD4007UBE using SDA. The alignment between the simulated and actual conditions is crucial because it validates the accuracy and reliability of the simulation model. Furthermore, closely matching the simulation model accurately represents the circuit's behavior in real scenarios.

# 4.2Graph analysis on the reference and sensing electrode equivalent circuit

In this part of the simulation, each component  $C_{REF}$ ,  $R_{REF}$ , R2, C1, and R1 was varied from low to a high value to observe the output changes in the  $I_D$  versus  $V_{GS}$  graph. The resistor was varied from 10  $\Omega$  to 1000 k $\Omega$ , while for capacitor was varied from 0.1  $\mu$ F to 4700  $\mu$ F. This indicates that different values were assigned to these components to assess the impact on the circuit's behavior, specifically the  $I_D$  versus  $V_{GS}$  relationship. By varying these components, the simulation can explore a range of possible circuit configurations and observe how these variations affect the output characteristics. Observing the output changes in the  $I_D$  versus  $V_{GS}$  graph makes it possible to identify trends, patterns, and relationships between

Table 2 Summarize	output	for each	component
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the component values and the resulting drain current. This analysis can provide insights into the circuit's performance, its sensitivity to component variations, and the range of values that yield desirable or optimal operation. Table 2 shows the current I<sub>D</sub> output when the component's value in the EGFET equivalent circuit was changed. The simulation results showed no changes in the drain current for the different values of R and C. This implies that altering the values of R and C did not significantly impact the drain current in this particular circuit. Therefore, due to no changes for each component, R2 has been replaced with the voltage source, V<sub>R2</sub>, by assuming the voltage source act as potential differences between the two electrodes, as shown in Figure 13. A voltage source can manipulate the circuit behavior and potentially influence the I<sub>D</sub> current. As shown in Table 3, as the value of  $V_{R2}$  increases, the  $I_D$  also increases. It shows that the potential difference at V<sub>R2</sub> may result in different output values indicating a clear correlation between the potential difference at V<sub>R2</sub> and the output values of I<sub>D</sub>. This situation obeys Nascimento and Mulato [45], in which there are potential differences between RE and SE. That the ions in the solution are eventually attached to the sensor's surface due to their affinity with these ions. Consequently, the voltage value will change according to a different solution and sensing film, then the result will lead to an extra variable potential  $\Delta V$  between the bulk solution and the film's surface.

<b>Reference Electrode(RE)</b>					Sensing Electrode(SE)		Output
V <sub>REF</sub> (V)	V <sub>DS</sub> (mV)	C <sub>REF</sub>	R <sub>REF</sub>	R2	C1	R2	$I_D/V_{GS}(\mu A)$
3	100	0.1µ	10	10	0.1µ	10-1000k	234.002
3	100	0.1µ	10	10	0.1-4700µ	10	234.002
3	100	0.1µ	10	10-1000k	0.1µ	10	234.002
3	100	0.1µ	10-1000k	10	0.1µ	10	234.002
3	100	0.1-4700µ	10	10	0.1µ	10	234.002



Figure 13 EGFET equivalent circuit with R2 changed to voltage  $V_{R2}$ 

		Reference	electrode		Sensing el	ectrode	Output
$V_{R2}(V)$	V <sub>DS</sub> (mV)	C <sub>REF</sub>	<b>R</b> <sub>REF</sub>	R2	C1	R2	$I_D/V_{GS}(A)$
0	100	0.1µ	$10\Omega$	10Ω	0.1µ	10Ω	234.00μ
1	100	0.1µ	$10\Omega$	10Ω	0.1µ	10Ω	360.85µ
2	100	0.1µ	$10\Omega$	10Ω	0.1µ	10Ω	486.97µ
3	100	0.1µ	$10\Omega$	10Ω	0.1µ	10Ω	613.46µ
4	100	0.1µ	$10\Omega$	10Ω	0.1µ	10Ω	739.95µ
5	100	0.1µ	10Ω	10Ω	0.1µ	10Ω	866.44µ
6	100	0.1µ	10Ω	$10\Omega$	0.1µ	10Ω	992.93µ
7	100	0.1µ	10Ω	$10\Omega$	0.1µ	$10\Omega$	1.119m
8	100	0.1µ	10Ω	10Ω	0.1µ	10Ω	1.246m
9	100	0.1µ	10Ω	10Ω	0.1µ	$10\Omega$	1.372m
10	100	0.1µ	10Ω	10Ω	0.1µ	$10\Omega$	1.499m

**Table 3** Summarize output for different  $V_{R2}$ 

*Figure 14 (a)-(d)* shows different configurations of the EGFET equivalent circuit to observe if there are any changes in the I<sub>D</sub> versus V<sub>GS</sub> graph. *Figure 14 (a)* is the same as *Figure 9*, *Figure 14 (b)* shows that all capacitors and resistors have been removed, while *Figure 14 (d)* only capacitor and resistor for the reference electrode part, and *Figure 14 (c)* capacitor and resistor R2.

By depicting different circuit configurations, it aims to explore the effects of these variations on the behavior of the  $I_D$  versus  $V_{GS}$  relationship. Each configuration likely involves modifications to specific components or connections within the circuit, potentially influencing its overall performance.



Figure 14 (a)-(d) EGFET equivalent circuit with R2 changed to voltage VR2

However, the simulation result shows the output for all equivalent circuits exhibited in the same graph where the value of  $I_D$  equals 234.002  $\mu$ A. But a notable change occurred when a capacitor was added in series with R2 (as depicted in *Figure 15*). The output graph in *Figure 16* indicated an output of 209 fA. This means that the presence of the capacitor significantly reduced the current. Furthermore, the 616

simulation was conducted with a fixed  $V_T$  value of 1.1V. Interestingly, the output current remained very small at 209 fA and was unaffected by changes in  $V_{GS}$ . However, when the  $V_T$  value was changed to 0V, the output characteristic exhibited an exponential curve, as shown in *Figure 17*. This suggests that the  $I_D$  current gradually increased as the VGS value increased from 0 to 3V.





Figure 16  $I_D$  versus  $V_{GS}$  graph for single capacitor C1



Figure 17  $I_D$  versus  $V_{GS}$  graph with  $V_T$  equal to 0 V

# 4.3Comparison of SPICE simulation and experimental results

Figure 18 and Figure 19 show the output and transfer characteristics measured by SDA with EGFET setup

at different pH values (pH 2, 4, 6, 7, 8, 10, and 12) using titanium dioxide (TiO<sub>2</sub>) SE data. The output characteristic shows that the  $I_D$  decreased as the pH value increased and that low pH yields a high  $I_D$ .

There is an inverse relationship between the pH value and the drain current. Additionally, it shows that low pH levels lead to higher drain currents. The drain current indicates this sensitivity, with higher currents indicating lower pH values and lower currents indicating higher pH values. This behavior is significant because it can be utilized for pH sensing applications or other relevant fields where pH detection is important.



Figure 18 Experimental  $I_D$  versus  $V_{DS}$  graph at different pH values



Figure 19 Experimental  $I_D$  versus  $V_{GS}$  graph at different pH values

Figure 20 displays a graph that represents the relationship between  $I_D$  and  $V_{DS}$  under different  $V_{REF}$  values. The graph was generated through LTSPICE simulation, utilizing an equivalent circuit shown in *Figure 10*. The pattern observed in *Figure 20* is similar to that of *Figure 18*, indicating that the drain current decreases as the pH value increases. The specific data points on the graph indicate that at pH 12, the drain current is approximately 500  $\mu$ A, while

at pH 2, it is around 50  $\mu$ A. The graph illustrates a linear and proportional relationship between I<sub>D</sub> and V<sub>DS</sub> until I<sub>D</sub> reaches saturation. At this point, the drain current remains constant for each pH value. *Figure 21* presents the graph depicting the relationship between I<sub>D</sub> and V<sub>GS</sub> under different V<sub>DS</sub> values obtained through LTSPICE simulation. It is observed that the I<sub>D</sub> varies with the V<sub>DS</sub> value. However, the initial V<sub>T</sub> remains consistent across all pH values. These findings diverge from the characteristics obtained in the experimental work, indicating the necessity for modification of the equivalent circuit.



Figure 20 Simulation  $I_{\rm D}$  versus  $V_{\rm DS}$  graph at different  $V_{REF}$  values



Figure 21 Simulation  $I_D$  versus  $V_{GS}$  graph at different  $V_{DS}$  values

Figure 22 illustrates the modified equivalent circuit with additional voltage,  $V_{SB}$ . The introduction of  $V_{SB}$  in the equivalent circuit significantly impacts the relationship between the  $I_D$  and the  $V_{GS}$ . The  $V_{SB}$  voltage affects the  $V_T$  of the transistor, which in turn influences the transistor's behavior in response to changes in  $V_{GS}$ . When  $V_{SB}$  is present, it creates a voltage difference between the transistor source and

the body, leading to the body effect. This voltage difference modifies the effective  $V_T$  and alters the transistor's turn-on and turn-off characteristics. Regarding the drain current versus  $V_{GS}$  relationship, the Body effect caused by  $V_{SB}$  introduces a second-gate control mechanism. The body, acting as a secondary gate, affects the effective gate voltage seen by the transistor. As a result, the transistor's behavior in terms of current flow and switching behavior is influenced by both the  $V_{GS}$  and the  $V_{SB}$  voltage [46].

By varying the  $V_{SB}$  and fixing the value of other components, it shows the different values of  $I_D$  at different values of  $V_T$  were obtained as shown in *Figure 23*. For example, at lower pH 2, the value of  $V_T$  was around 5.5 V; for pH 12 the value of  $V_T$  was around 1.15 V, which is a similar pattern to the experimental results.



Figure 22 Modified equivalent circuit with additional voltage,  $V_{SB}$ 



Figure 23 Simulation graph with varying V<sub>SB</sub>

### **5.Discussion**

This study focuses on simulating the EGFET equivalent circuit and various types of equivalent circuits using LTSPICE XVII with discrete components. The accurate modeling and simulation achieved in this research hold the potential to contribute significantly to the prediction of output

current based on different pH levels. The results indicate a close resemblance between the simulation graph of transfer characteristics and the SDA. However, a slight disparity is observed in the output characteristic graph, particularly in terms of the drain saturation current value. Notably, the resistor and capacitor values in the equivalent circuit exhibit negligible influence on the transfer and output characteristics. Conversely, parameters associated with the MOSFET, such as width, length, transconductance, and threshold voltage, play a vital role in determining device behavior. Furthermore, the inclusion of the modified equivalent circuit with an additional voltage, V<sub>SB</sub>, results in varying V<sub>T</sub> values corresponding to different pH levels, which aligns with the experimental findings.

In addition, the study ensures a more realistic representation of the circuit by employing discrete components in the simulation. This contributes to the advancement of pH-based current prediction, which has potential applications in various fields, such as biomedical sensing and environmental monitoring. Comparing the simulation results with SDA, a commonly used analysis technique, validates the accuracy of the simulated transfer characteristics. However, a slight discrepancy in the output characteristics, specifically in the drain saturation current value, suggests that further refinement may be necessary for the model or simulation setup to achieve a closer match to experimental observations. It is crucial to investigate the factors causing this disparity and explore potential improvements to enhance the accuracy of the output characteristics simulation

The findings regarding the resistor and capacitor values indicate their limited influence on the transfer and output characteristics, emphasizing that the MOSFET parameters play a more significant role in shaping the device behavior. This underscores the importance of accurately characterizing and modeling the MOSFET parameters, such as width, length, transconductance, and threshold voltage, to ensure reliable simulation results.

Furthermore, incorporating the additional voltage,  $V_{SB}$ , in the modified equivalent circuit demonstrates its ability to produce varying  $V_T$  values corresponding to different pH levels, like what is observed in experimental results. This highlights the effectiveness of the proposed modification in capturing the influence of pH on the device's behavior.

### **5.1Limitations**

The accuracy of the electrochemical equivalent circuit largely depends on the circuit components' accuracy and values. Therefore, the experimental values used to obtain these component values may be unclear, affecting the quality of the simulation findings. On the other hand, the electrochemical equivalent circuit is a simplified representation of the complex electrochemical processes that occur in the pH sensor. It is based on linear behavior and ignores various nonlinearities and interdependencies between components. This simplification may result in discrepancies between the simulated and actual sensor responses.

A complete list of abbreviations is shown in *Appendix I*.

## **6.**Conclusion and future work

This study successfully simulated the EGFET equivalent circuits using LTSPICE XVII with discrete components. The research employs precise modeling and simulation techniques that have significant potential in forecasting the output current in relation to varying pH levels. The findings indicate that the simulation graph of transfer characteristics corresponds closely to the SDA, although there is a slight difference in the output characteristic graph, particularly in the value of the drain saturation current. The transfer and output characteristics of the equivalent circuit were found to be minimally affected by the values of the resistor and capacitor. However, the MOSFET parameters, including width, length, transconductance, and threshold voltage, were crucial in determining the device's behavior. Moreover, the inclusion of the modified equivalent circuit with an additional voltage, V<sub>SB</sub>, successfully generated varying V<sub>T</sub> values corresponding to different pH levels, aligning with experimental findings. In addition, the accuracy of the simulated transfer characteristics was validated by comparing the simulation results with the commonly used SDA analysis technique. There appears to be a minor inconsistency in the output characteristics, specifically in the value of the drain saturation current. It can be concluded that additional model or simulation setup improvements are necessary to achieve a more accurate alignment with experimental observations. Thus, future work may conduct a sensitivity analysis on the MOSFET parameters such as width, length, transconductance, and threshold voltage. Systematically varying these parameters within a reasonable range and observing the resulting changes in the transfer and output characteristics could help to identify the most influential parameters and fine-tune the values to enhance accuracy and reliability.

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### **Conflicts of interest**

The authors have no conflicts of interest to declare.

### Author's contribution statement

Shaiful Bakhtiar Hashim: Design circuit, simulation, data collection, writing original draft and editing. Muhammad Alhadi Zulkefle: Carried out the experiment and data collection. Zurita Zulkifli: Anchored the review, revisions, and approved the article submission. Sukreen Hana Herman: Conceptualized the central research idea, and provided the theoretical framework.

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Appendix I				
S. No.	Abbreviation	Description		
1	BJT	Bipolar Junction Transistors		
2	CAD	Computer-Aided Design		
3	EGFET	Extended-Gate Field Effect		
		Transistor		
4	FET	Field Effect Transistor		
5	ID	Drain Current		
6	ISE	Ion-Selective Electrodes		
7	ISFET	Ion-Sensitive Field Effect		
		Transistor		
8	MOSFET	Metal Oxide Semiconductor		
		Field-Effect Transistor		
9	NMOS	N-type Metal Oxide		
		Semiconductor		
10	PDI	Potential Determining Ions		
11	PMOS	P-type Metal Oxide		
		Semiconductor		
12	RE	Reference Electrode		
13	SDA	Semiconductor Device		
		Analyzer		
14	SE	Sensing Electrode		
15	SPICE	Simulation Program with		
		Integrated Circuit Emphasis		
16	TiO <sub>2</sub>	Titanium Dioxide		
17	V <sub>DS</sub>	Drain to Source Voltage		
18	V <sub>GS</sub>	Gate to Source Voltage		
19	V <sub>REF</sub>	Reference Voltage		
20	VT	Threshold Voltage		